US00D828190S

(12) **United States Design Patent**
Makino

(10) **Patent No.:** **US D828,190 S**
(45) **Date of Patent:** ** **Sep. 11, 2018**

(54) **PROBE**

(71) Applicant: **SINTOKOGIO, LTD.**, Nagoya-shi, Aichi (JP)

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(73) Assignee: **SINTOKOGIO, LTD.** (JP)

(**) Term: **15 Years**

(21) Appl. No.: **29/598,352**

(22) Filed: **Mar. 24, 2017**

(30) **Foreign Application Priority Data**

Oct. 3, 2016 (JP) 2016-021519

(51) **LOC (11) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/80**

(58) **Field of Classification Search**
USPC D10/46, 75, 78, 78.8, 100, 80; D13/107; D14/128, 221, 225, 231, 388, 434; D15/199
CPC G01N 27/82; G01N 27/83; G01N 27/87; G01N 27/90; G01N 27/9033; G01N 27/9026; G01N 27/902; G01N 27/9006; G01N 27/9013
See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a probe showing my new design;

FIG. **2** is a front view thereof, the rear view being a mirror image thereof;

FIG. **3** is a left side view thereof;

FIG. **4** is a right side view thereof;

FIG. **5** is a top plan view thereof; and,

FIG. **6** is a bottom plan side view thereof.

The parallel dash-dot broken lines represent a symbolic break and form no part of the claimed design.

1 Claim, 3 Drawing Sheets

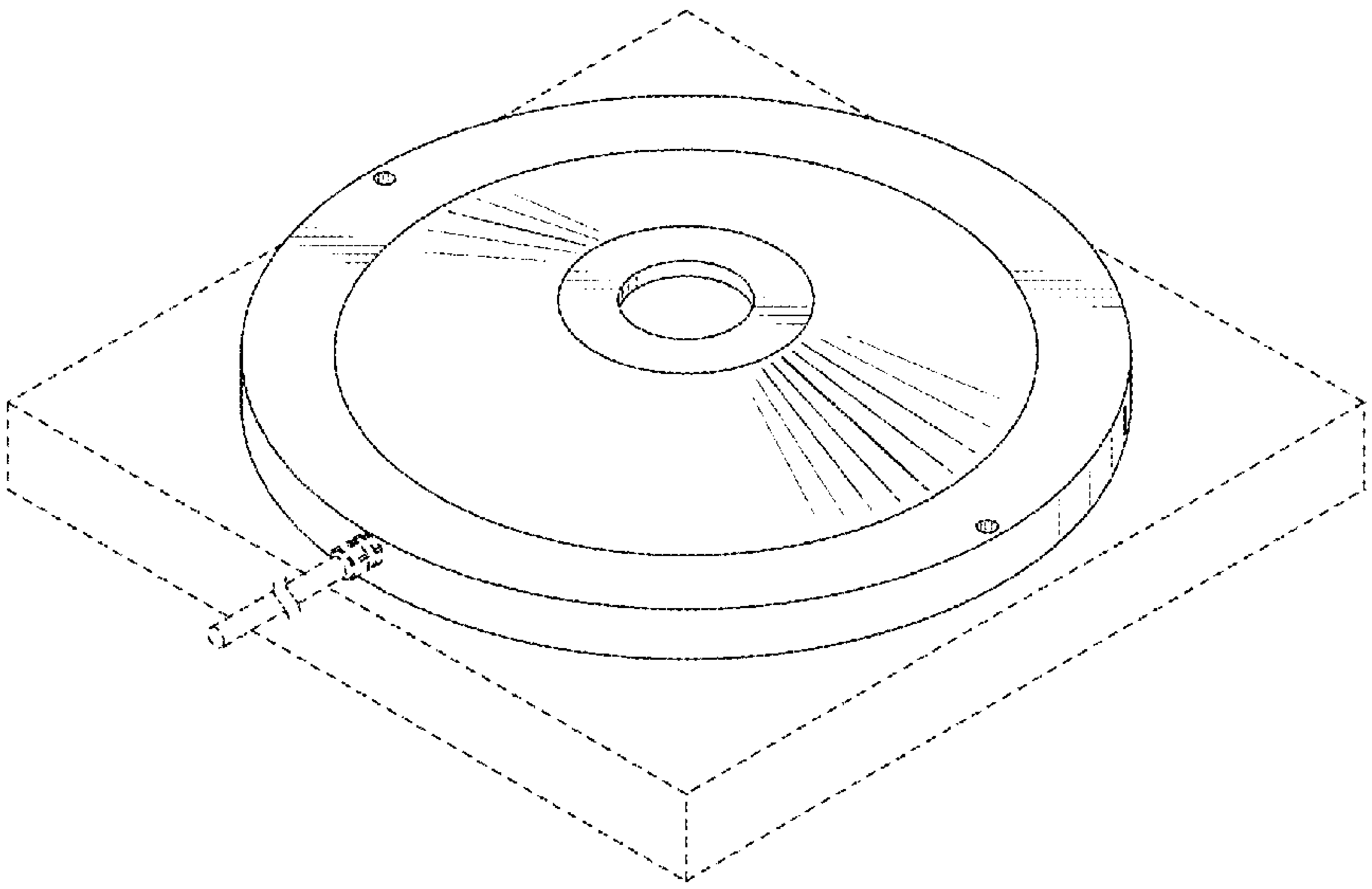


FIG.1

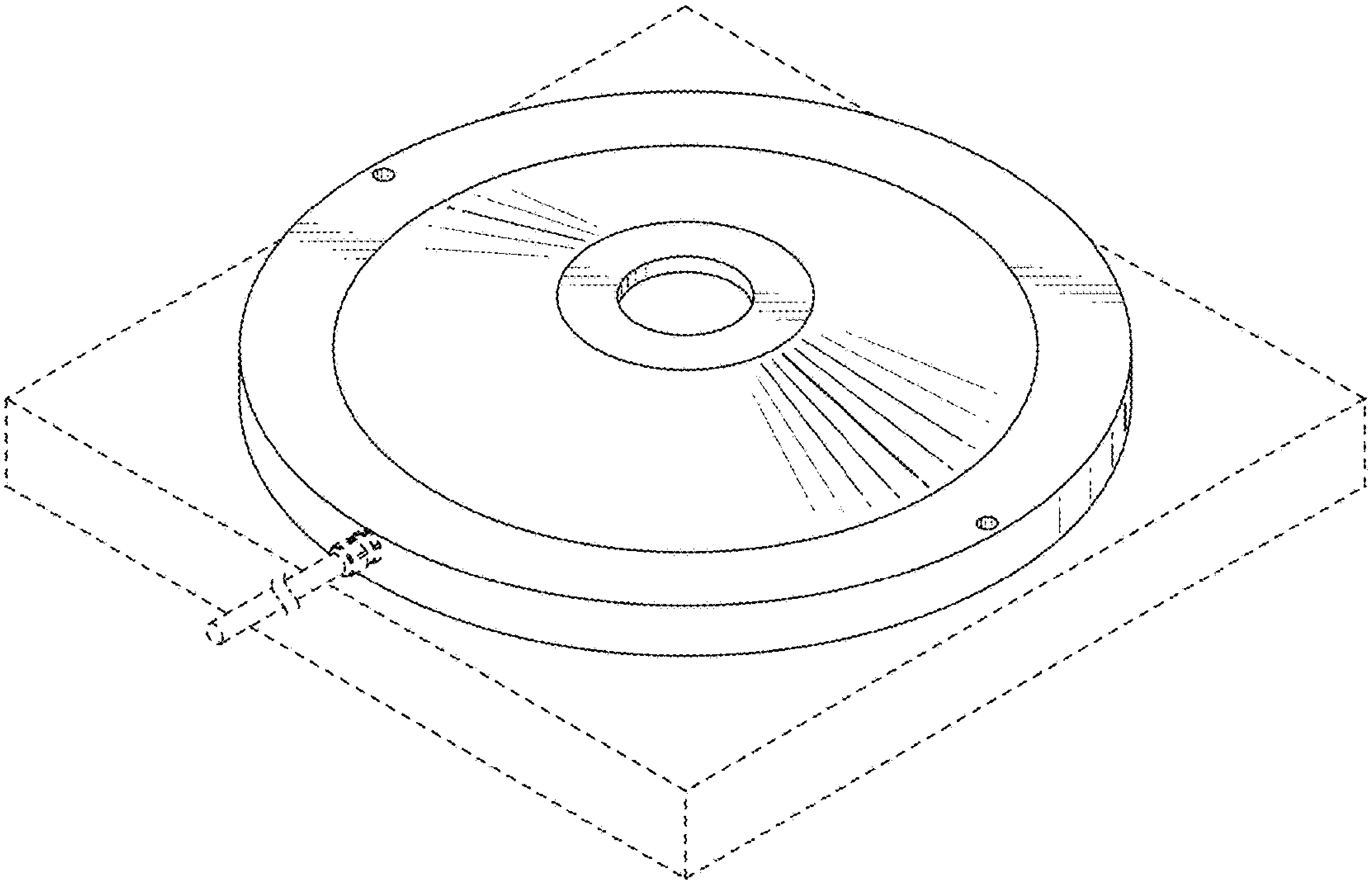


FIG.2

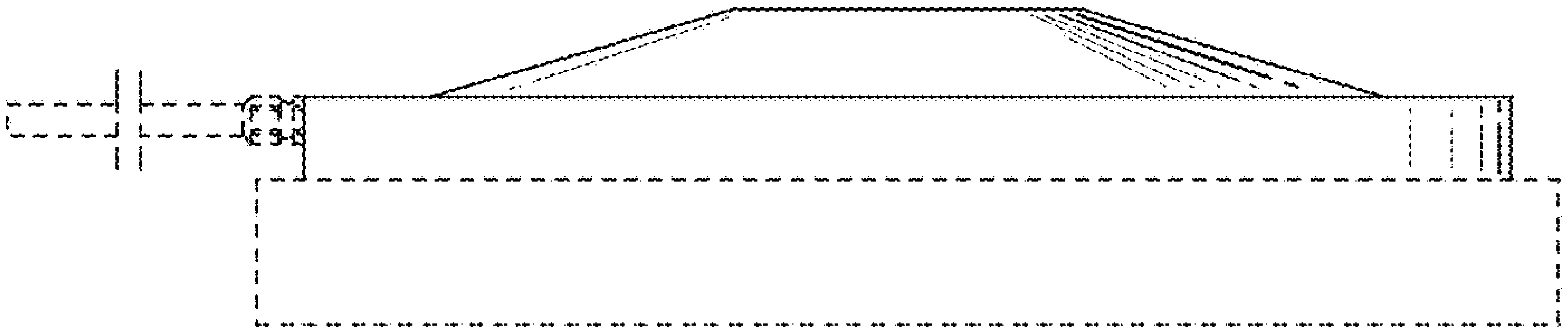


FIG.3

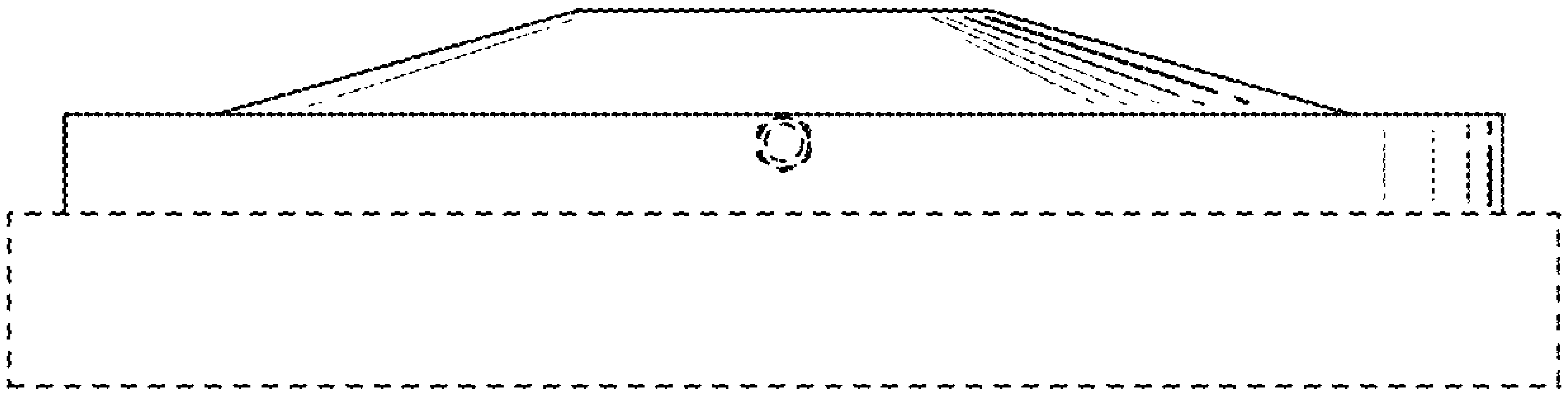


FIG.4

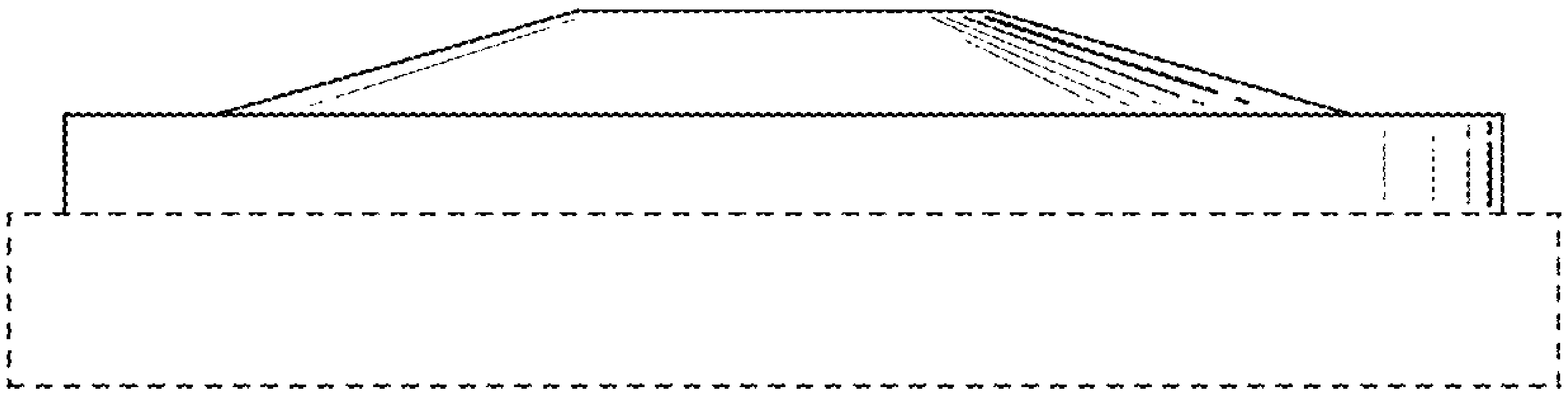


FIG.5

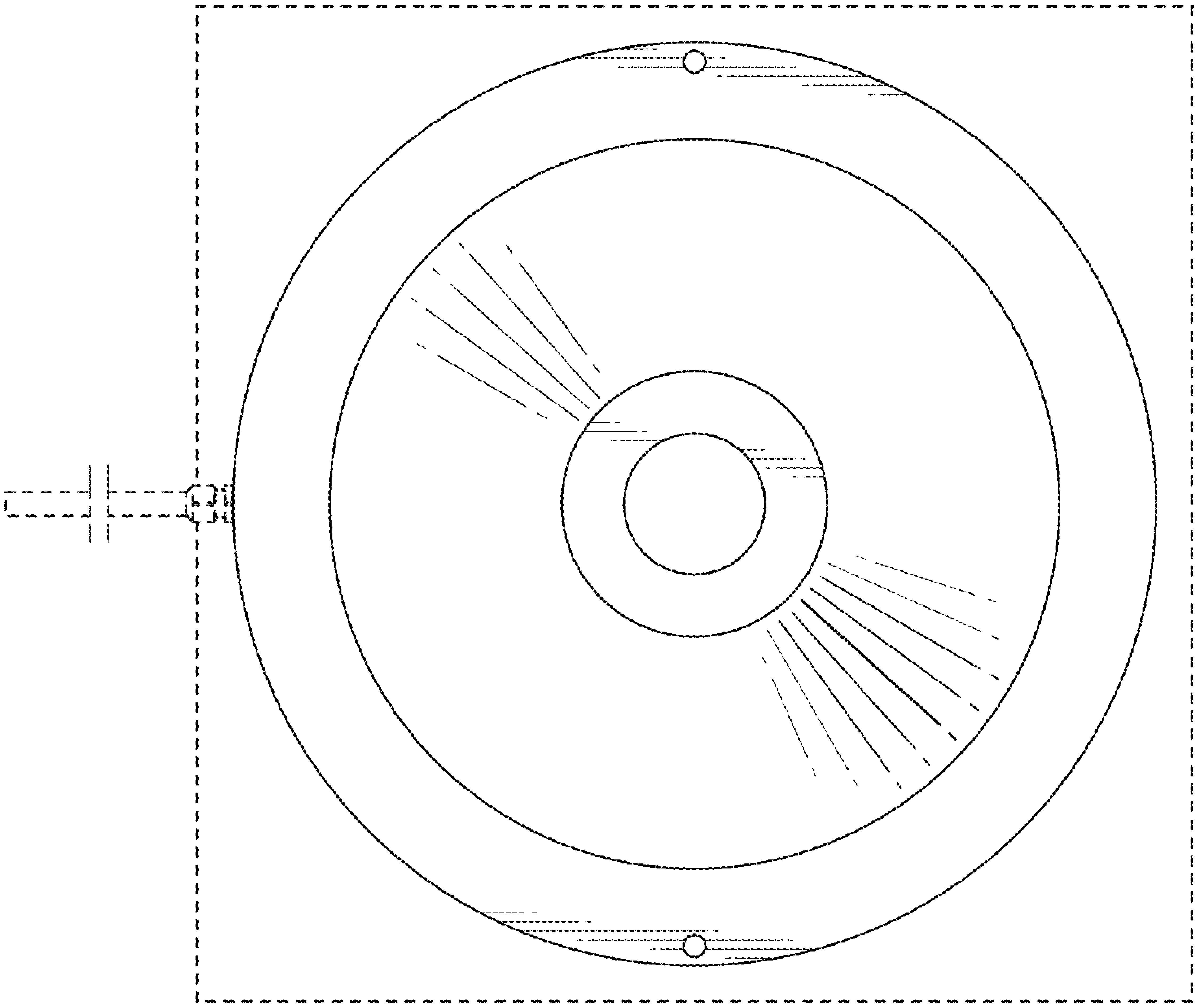
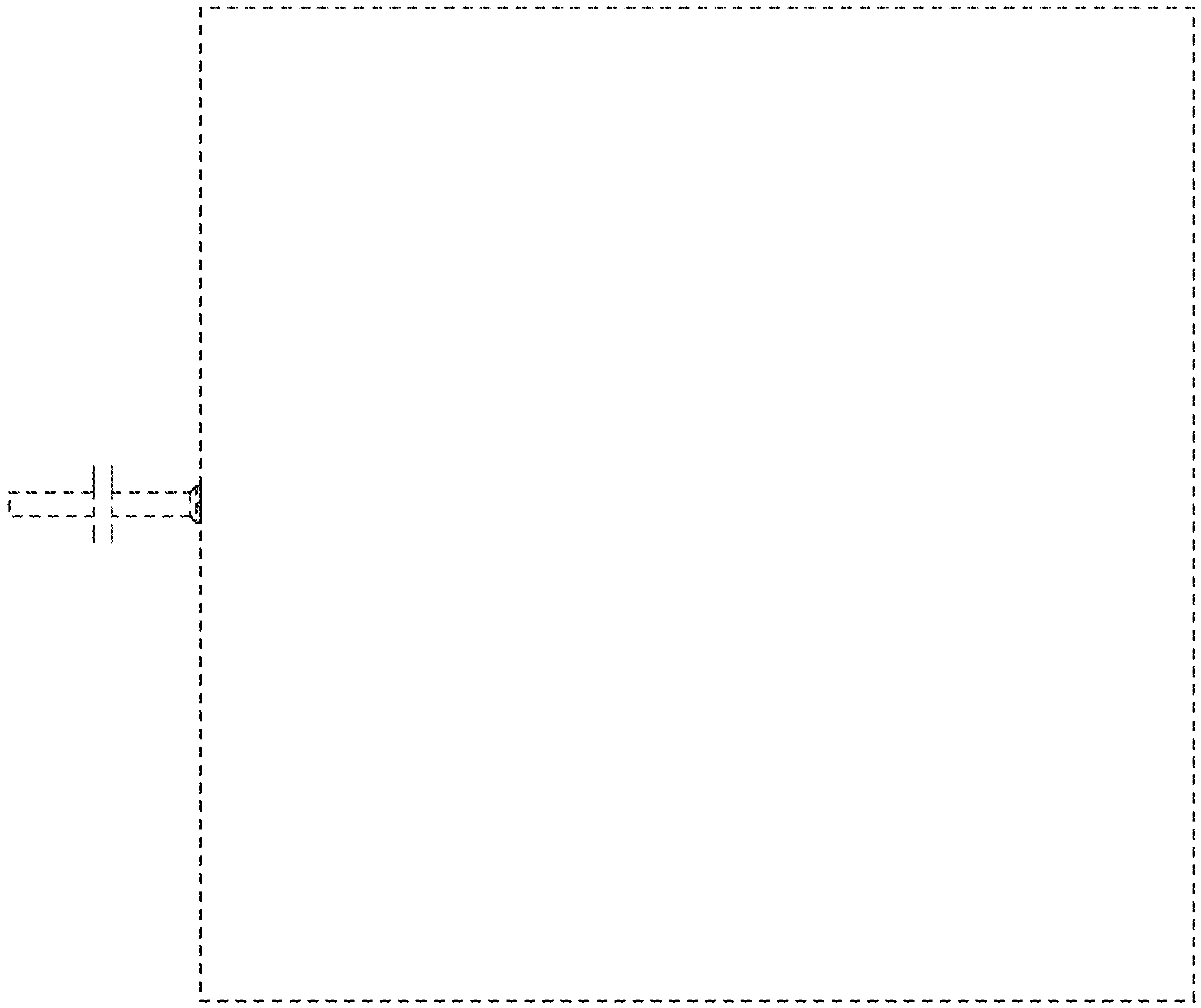


FIG.6



UNITED STATES PATENT AND TRADEMARK OFFICE

CERTIFICATE OF CORRECTION

PATENT NO. : D828,190 S
APPLICATION NO. : 29/598352
DATED : September 11, 2018
INVENTOR(S) : Yoshiyazu Makino

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

On the Title Page

Description should read:
FIG. 1 is a perspective view of a probe showing my new design;
FIG. 2 is a front view thereof, the rear view being a mirror image thereof;
FIG. 3 is a left side view thereof;
FIG. 4 is a right side view thereof;
FIG. 5 is a top plan view thereof; and
FIG. 6 is a bottom plan side view thereof.
The broken lines show portions of the probe that form no part of the claimed design. The drawings include surface shading which represents contour and not surface ornamentation.
The parallel dash-dot-dash broken lines represent a symbolic break and form no part of the claimed design.

Signed and Sealed this
Twenty-seventh Day of November, 2018

Andrei Iancu

Andrei Iancu
Director of the United States Patent and Trademark Office